

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10811320	TANI ET AL.
	<b>Examiner</b> Lafond, Ronald D	<b>Art Unit</b> 1709

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
427	565	06/1/20075	RDL

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Spoke with Michael Cleveland about search terms, USPCs	04/05/2007	RDL
Performed text search in EAST; see EAST Search History	04/05/2007	RDL
Examined International Search Report	04/05/2007	RDL
Examined PLUS Search Results	04/05/2007	RDL
Requested translation of Japanese documents cited in International Search Report	04/11/2007	RDL
Requested STIC search	06/11/2007	RDL
Consulted with Shrive Beck	06/18/2007	RDL

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>